

Notice of References Cited	Application/Control No. 10/695,890	Applicant(s)/Patent Under Reexamination SEKINE ET AL.	
	Examiner Hong C. Kim	Art Unit 2186	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0148484	07-2004	Watanabe et al.	711/170
	B	US-2004/0111251	06-2004	Trimmer et al.	703/026
	C	US-2004/0098244	05-2004	Dailey et al.	703/024
	D	US-2004/0044855	03-2004	Carlson et al.	711/154
	E	US-2003/0154340	08-2003	Bolt et al.	710/305
	F	US-2003/0135672	07-2003	Yip et al.	710/72
	G	US-2003/0037211	02-2003	Winokur, Alexander	711/162
	H	US-2002/0144044	10-2002	Moon et al.	710/302
	I	US-6,701,455	03-2004	Yamamoto et al.	714/18
	J	US-6,557,073	04-2003	Fujiwara et al.	711/111
	K	US-6,128,698	10-2000	Georgis, Steven P.	711/111
	L	US-5,438,674	08-1995	Keele et al.	711/4
	M	US-5,297,124	03-1994	Plotkin et al.	360/49

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

12h